

Notice of References Cited

Application/Control No.

10/811,260

Applicant(s)/Patent Under
Reexamination
ARBUTHNOT ET AL.

Examiner

Celia Chang

Art Unit

1625

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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FOREIGN PATENT DOCUMENTS

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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Webster's II dictionary, p.286 (1984)
	V	Nystrom et al. "Comparison of permeametry and photometry for the measurement of" CA 88:126272 (1978)
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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